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**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Patent Application of

HARADA ET AL.

Atty. Ref.: 4923-2

Serial No. Unknown

TC/A.U.: Unknown

Filed: July 6, 2006

Examiner: Unknown

For: INTERFEROMETER

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July 6, 2006

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

Sir:

**INFORMATION DISCLOSURE STATEMENT**

As suggested by 37 C.F.R. 1.97, the undersigned attorney brings to the attention of the Patent and Trademark Office the references listed on the attached form PTO/SB/08a. A copy of each listed foreign patent document and article is attached.

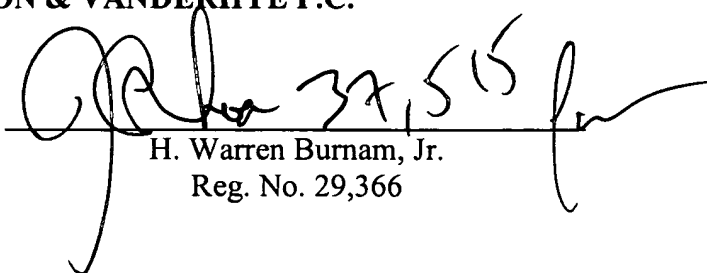
This is not to be construed as a representation that a search has been made or that no better prior art exists, or that a reference is relevant merely because cited.

The Examiner is requested to initial the attached form PTO/SB/08a and to return a copy of the initialed document to the undersigned as an indication that the attached references have been considered and made of record.

Respectfully submitted,

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## SERIAL NO. \_\_\_\_\_

Unknown

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FILING DATE

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[illegible]

FOREIGN PATENT DOCUMENTS							TRANSLATION	
DOCUMENT			DATE	COUNTRY	CLASS	SUBCLASS	YES	NO
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		10-199464	7/1998	JP				
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	International Search Report for PCT/JP2005/000111 dated 19 April 2005 (English and Japanese).
	Ru et al., <i>Electron holography available in a non-biprism transmission electron microscopy</i> , Ultramicroscopy 53, 1 (1994), pp. 1-7.
	Harada et al., <i>Profile structure of magnetic flux lines in type-II superconductor from a rectangular electron hologram</i> , Journal of Electron Microscopy, 52 (4), 2003, pp. 369-373.
	Harada et al., <i>A New FET Method for Numerical Reconstruction in Electron Holography</i> , Journal of Electron Microscopy, 40, 1991, pp. 92-96.
	Zernike, <i>The Construction of Degree of Coherence and Its Application to Optical Problems</i> , Physica V, no. 8, August 1938, pp. 785-795.
	Thompson et al., <i>Two-Beam Interference with Partially Coherent Light</i> , Journal of the Optical Society of America, Vol. 47, No. 10, October 1957, pp. 895-902.
	Speidel et al., <i>Richtstrahlwertmessungen an einem Strahlerzeugungssystem mit Feldemissionskathode</i> , Optik 49, No. 2, 1977, pp. 173-185.
	Harada et al., <i>Optical Simulation for Electron Holography</i> , Technology Reports of the Osaka University, Vol. 39, No. 1960 (October 1989), pp. 117-128.

Date Considered

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